

MOSFET

StrongIRFET™ 2 Power-Transistor, 30 V

Features

- Optimized for wide range of applications
- N-channel, logic level
- 100% avalanche tested
- 175°C rated
- Pb-free lead plating; RoHS compliant
- Halogen-free according to IEC61249-2-21

Product validation

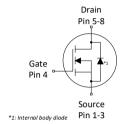
Qualified according to JEDEC Standard

Table 1 Key Performance Parameters

Parameter	Value	Unit
$V_{ m DS}$	30	V
$R_{\mathrm{DS(on),max}}$	3.3	mΩ
I_{D}	109	А
Q _{oss}	17	nC
Q _G (0V4.5V)	10	nC

PG-TSDSON-8 FL









Type/Ordering Code	Package	Marking	Related Links
ISZ033N03LF2S	PG-TSDSON-8	033N03F	-

Public

StronglRFET™ 2 Power-Transistor, 30 V ISZ033N03LF2S



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StrongIRFET™ 2 Power-Transistor, 30 V ISZ033N03LF2S



1 Maximum ratings

at T_{Δ} =25 °C, unless otherwise specified

Table 2 Maximum ratings

Parameter	Symbol	Values			Linit	Nieto/Tost Condition
raiailletei	Syllibot	Min.	Тур.	Мах.	Unit	Note/ Test Condition
Continuous drain current ¹⁾	I _D	-	-	109 77 20	A	$V_{\rm GS}$ =10 V, $T_{\rm C}$ =25 °C $V_{\rm GS}$ =10 V, $T_{\rm C}$ =100 °C $V_{\rm GS}$ =10 V, $T_{\rm A}$ =25 °C, $R_{\rm THJA}$ =60 °C/W ²⁾
Pulsed drain current ³⁾	I _{D,pulse}	-	-	436	А	<i>T</i> _A =25 °C
Avalanche energy, single pulse ⁴⁾	E _{AS}	-	-	107 215	mJ	$I_{\rm D}$ =20 A, $R_{\rm GS}$ =25 Ω $I_{\rm D}$ =10 A, $R_{\rm GS}$ =25 Ω
Gate source voltage	V_{GS}	-20	-	20	V	-
Power dissipation	P_{tot}	-	-	71 3.0	W	$T_{\rm C}$ =25 °C $T_{\rm A}$ =25 °C, $R_{\rm THJA}$ =50 °C/W ²⁾
Operating and storage temperature	$T_{\rm j}$, $T_{\rm stg}$	-55	-	175	°C	-

¹⁾ Rating refers to the product only with datasheet specified absolute maximum values, maintaining case temperature as specified. For other case temperatures please refer to Diagram 2. De-rating will be required based on the actual environmental conditions.

²⁾ Device on 40 mm x 40 mm x 1.5 mm epoxy PCB FR4 with 6 cm² (one layer, 70 μm thick) copper area for drain connection. PCB is vertical in still air.

³⁾ See Diagram 3 for more detailed information

⁴⁾ See Diagram 13 for more detailed information

StronglRFET™ 2 Power-Transistor, 30 V ISZ033N03LF2S



2 Thermal characteristics

Table 3 Thermal characteristics

Davamakav	Symbol	Values			l lmi4	Note/ Test Condition
Parameter	Symbol	Min.	Тур.	Мах.	Unit	Note/ Test Condition
Thermal resistance, junction - case	R_{thJC}	-	-	2.1	°C/W	-
Thermal resistance, junction - case, top	R_{thJC}	-	-	20	°C/W	-
Device on PCB, 6 cm ² cooling area ⁵⁾	R_{thJA}	-	-	60	°C/W	-

Device on 40 mm x 40 mm x 1.5 mm epoxy PCB FR4 with 6 cm 2 (one layer, 70 μ m thick) copper area for drain connection. PCB is vertical in still air.

StronglRFET™ 2 Power-Transistor, 30 V ISZ033N03LF2S



3 Electrical characteristics

at T_i =25 °C, unless otherwise specified

Table 4 Static characteristics

Parameter	Symbol	Values			Unit	Nieto/Tost Condition
raiailletei	Syllibol	Min.	Тур.	Мах.	Offic	Note/ Test Condition
Drain-source breakdown voltage	$V_{(BR)DSS}$	30	-	-	V	$V_{\rm GS}$ =0 V, $I_{\rm D}$ =1 mA
Gate threshold voltage	$V_{\rm GS(th)}$	1.35	1.85	2.35	V	$V_{\rm DS} = V_{\rm GS}, I_{\rm D} = 30 \ \mu A$
Zero gate voltage drain current	I _{DSS}	-	0.1 10	1 100	μΑ	$V_{\rm DS}$ =30 V, $V_{\rm GS}$ =0 V, $T_{\rm j}$ =25 °C $V_{\rm DS}$ =30 V, $V_{\rm GS}$ =0 V, $T_{\rm j}$ =125 °C
Gate-source leakage current	I_{GSS}	-	10	100	nA	$V_{\rm GS}$ =20 V, $V_{\rm DS}$ =0 V
Drain-source on-state resistance	$R_{\mathrm{DS(on)}}$	-	2.8 3.8	3.3 5.7	mΩ	$V_{\rm GS}$ =10 V, $I_{\rm D}$ =20 A $V_{\rm GS}$ =4.5 V, $I_{\rm D}$ =10 A
Gate resistance	R_{G}	-	2.4	-	Ω	-
Transconductance ⁶⁾	g_{fs}	35	-	-	S	$ V_{\rm DS} \ge 2 I_{\rm D} R_{\rm DS(on)max}, I_{\rm D} = 20 \text{ A}$

⁶⁾ Defined by design. Not subject to production test.

Table 5 Dynamic characteristics

Darameter	Symbol	Values			Unit	Nieto/Tost Condition
Parameter	Syllibol	Min.	Тур.	Мах.		Note/ Test Condition
Input capacitance	C _{iss}	-	1415	-	pF	V _{GS} =0 V, V _{DS} =15 V, <i>f</i> =1 MHz
Output capacitance	C_{oss}	-	285	-	pF	$V_{\rm GS}$ =0 V, $V_{\rm DS}$ =15 V, f =1 MHz
Reverse transfer capacitance	C _{rss}	-	82	-	pF	$V_{\rm GS}$ =0 V, $V_{\rm DS}$ =15 V, f =1 MHz
Turn-on delay time	$t_{\sf d(on)}$	-	9.7	-	ns	$V_{\rm DD}$ =15 V, $V_{\rm GS}$ =4.5 V, $I_{\rm D}$ =20 A, $R_{\rm G,ext}$ =1.6 Ω
Rise time	t _r	_	5.7	-	ns	$V_{\rm DD}$ =15 V, $V_{\rm GS}$ =4.5 V, $I_{\rm D}$ =20 A, $R_{\rm G,ext}$ =1.6 Ω
Turn-off delay time	$t_{ m d(off)}$	-	9.9	-	ns	$V_{\rm DD} = 15 \text{ V}, V_{\rm GS} = 4.5 \text{ V}, I_{\rm D} = 20 \text{ A},$ $R_{\rm G,ext} = 1.6 \Omega$
Fall time	t _f	_	6.2	-	ns	$V_{\rm DD} = 15 \text{ V}, V_{\rm GS} = 4.5 \text{ V}, I_{\rm D} = 20 \text{ A},$ $R_{\rm G,ext} = 1.6 \Omega$

Table 6 Gate charge characteristics 7)

Parameter	Symbol	Values			Unit	Note/ Test Condition
raiailietei	Syllibol	Min.	Тур.	Мах.	Oilit	Note/ Test Condition
Gate to source charge	$Q_{ m gs}$	-	4.6	-	nC	$V_{\rm DD}$ =15 V, $I_{\rm D}$ =20 A, $V_{\rm GS}$ =0 to 4.5 V
Gate charge at threshold	$Q_{\mathrm{g(th)}}$	-	2.6	-	nC	$V_{\rm DD}$ =15 V, $I_{\rm D}$ =20 A, $V_{\rm GS}$ =0 to 4.5 V
Gate to drain charge	$Q_{ m gd}$	-	3.1	-	nC	$V_{\rm DD}$ =15 V, $I_{\rm D}$ =20 A, $V_{\rm GS}$ =0 to 4.5 V
Switching charge	Q_{sw}	-	5.1	-	nC	$V_{\rm DD}$ =15 V, $I_{\rm D}$ =20 A, $V_{\rm GS}$ =0 to 4.5 V
Gate charge total ⁸⁾	Q_{g}	-	10	15	nC	$V_{\rm DD}$ =15 V, $I_{\rm D}$ =20 A, $V_{\rm GS}$ =0 to 4.5 V

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Table 6 Gate charge characteristics 7)

Davamatar	Symbol	Values			1164	Note / Test Condition
Parameter	Symbol	Min.	Тур.	Мах.	Unit	Note/ Test Condition
Gate plateau voltage	$V_{ m plateau}$	-	3.2	-	V	$V_{\rm DD}$ =15 V, $I_{\rm D}$ =20 A, $V_{\rm GS}$ =0 to 4.5 V
Gate charge total ⁸⁾	$Q_{ m g}$	-	21	28	nC	$V_{\rm DD}$ =15 V, $I_{\rm D}$ =20 A, $V_{\rm GS}$ =0 to 10 V
Gate charge total, sync. FET	$Q_{g(sync)}$	-	8.9	-	nC	$V_{\rm DS}$ =0.1 V, $V_{\rm GS}$ =0 to 4.5 V
Output charge	$Q_{\rm oss}$	-	17	-	nC	$V_{\rm DS}$ =15 V, $V_{\rm GS}$ =0 V

 $^{^{7)}\ \ \, \}text{See}$ "Gate charge waveforms" for parameter definition

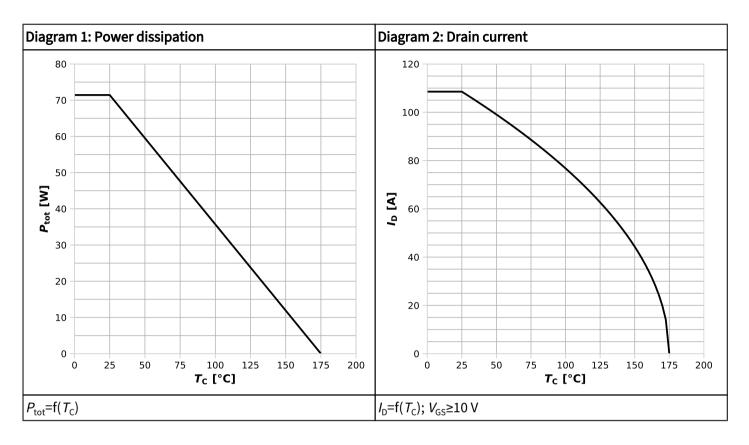
Table 7 Reverse diode

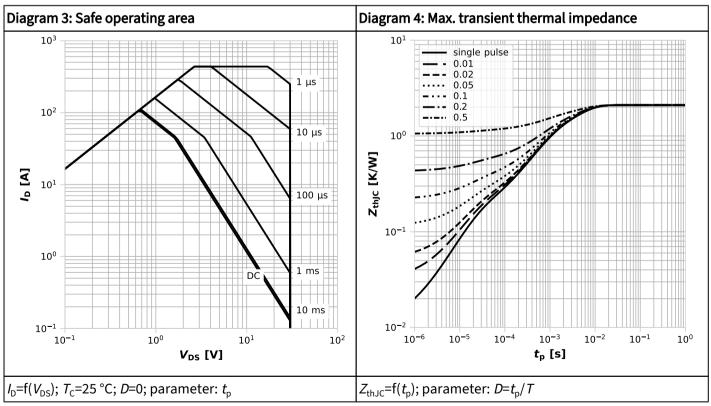
Parameter	Symbol	Values			Unit	Note / Test Condition
	Symbol	Min.	Тур.	Мах.	Ollit	Note/ Test Condition
Diode continuous forward current	I _S	-	-	67	Α	<i>T</i> _C =25 °C
Diode pulse current	I _{S,pulse}	-	-	436	Α	<i>T</i> _C =25 °C
Diode forward voltage	$V_{\rm SD}$	-	0.79	1.0	V	$V_{\rm GS}$ =0 V, $I_{\rm F}$ =20 A, $T_{\rm j}$ =25 °C
Reverse recovery time	t _{rr}	-	13	-	ns	$V_{\rm R}$ =15 V, $I_{\rm F}$ =20 A, d $i_{\rm F}$ /d t =500 A/ μ s
Reverse recovery charge	$Q_{\rm rr}$	-	28	-	nC	$V_{\rm R}$ =15 V, $I_{\rm F}$ =20 A, d $i_{\rm F}$ /d t =500 A/ μ s

⁸⁾ Defined by design. Not subject to production test.

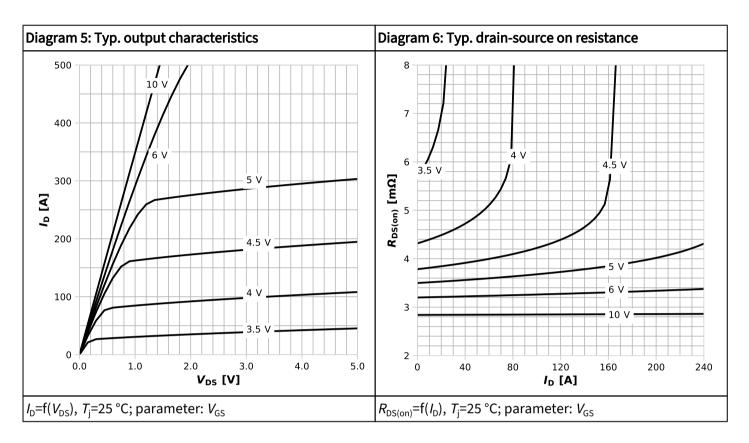


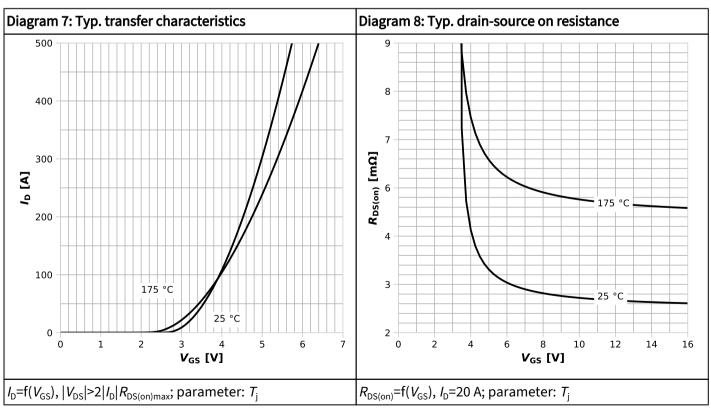
4 Electrical characteristics diagrams



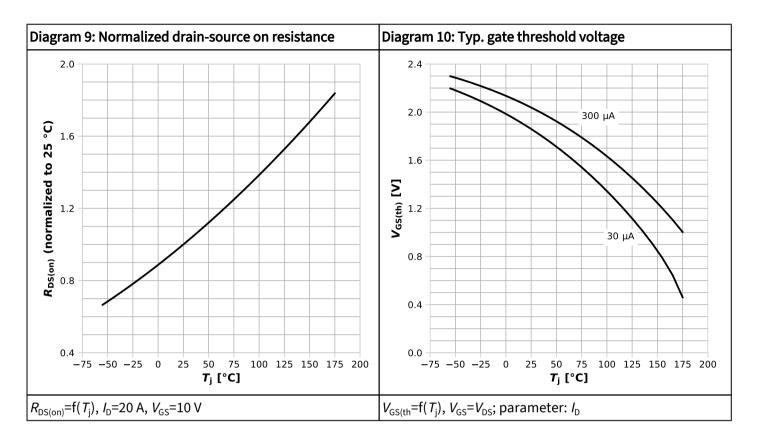


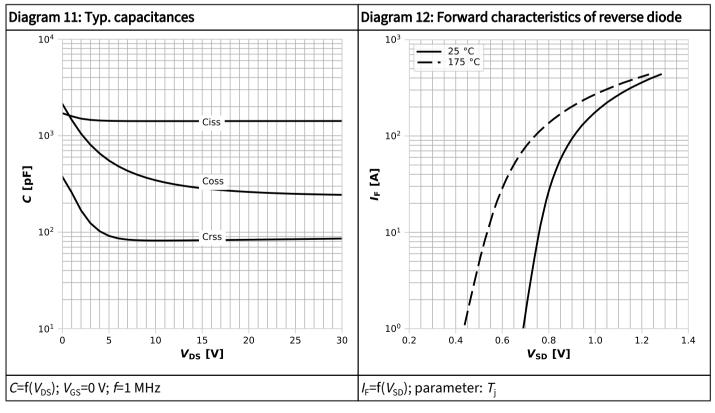




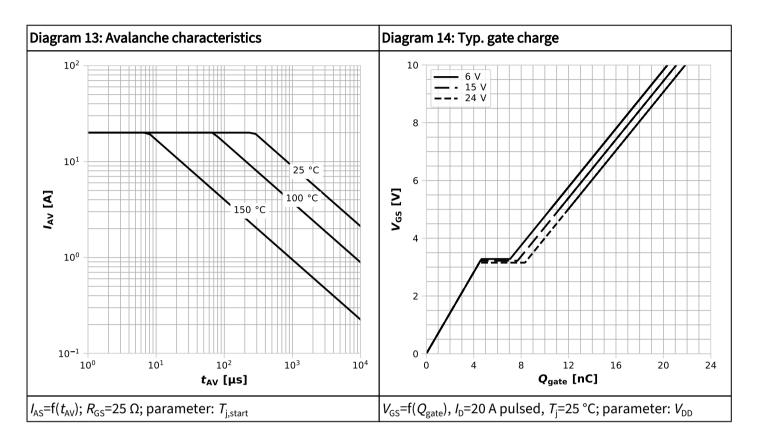


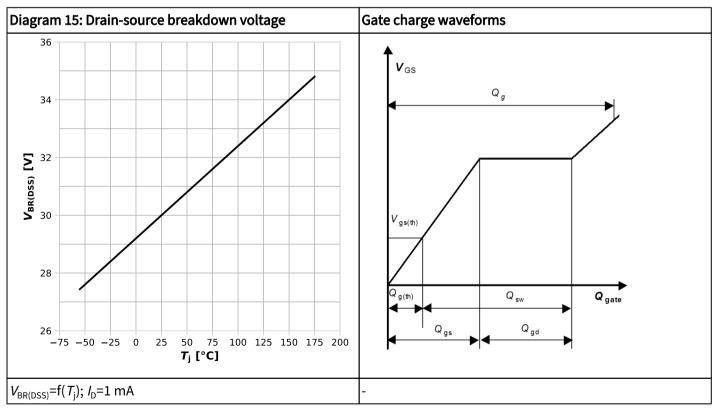






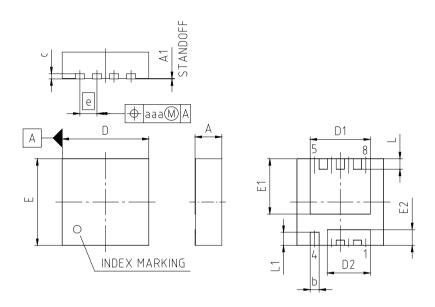








5 Package Outlines



PACKAGE - GROUP NUMBER:	PG-TSDS	PG-TSDSON-8-U03					
DIMENSIONS	MILLIMETERS						
DIMENSIONS	MIN.	MAX.					
Α	0.90	1.10					
A1	0	0.05					
b	0.24	0.44					
С	0.10	0.30					
D	3.20	3.40					
D1	2.19	2.39					
D2	1.54	1.74					
E	3.20	3.40					
E1	2.01	2.21					
E2	0.50	0.70					
е	0.	65					
L	0.30	0.50					
L1	0.40	0.60					
aaa	0.0	06					
N	8	1					

NOTE:

DIMENSIONS DO NOT INCLUDE MOLD FLASH, PROTRUSION OR GATE BURRS

Figure 1 Outline PG-TSDSON-8, dimensions in mm

StrongIRFET™ 2 Power-Transistor, 30 V ISZ033N03LF2S



Revision History

ISZ033N03LF2S

Revision 2024-10-12, Rev. 1.0

Previous Revision

Revision	Date	Subjects (major changes since last revision)
1.0	2024-10-12	Release of final

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